ANALOG DEVICES

CMOS
Low Voltage 4 Ω Quad SPST Switches

ADG711/ADG712/ADG713

FEATURES
1.8 V to 5.5 V Single Supply
Low On Resistance (2.5 Ω Typ)
Low On Resistance Flatness
–3 dB Bandwidth > 200 MHz
Rail-to-Rail Operation
16-Lead TSSOP and SOIC Packages
Fast Switching Times
    t_{ON} 16 ns
    t_{OFF} 10 ns
Typical Power Consumption (< 0.01 μW)
TTL/CMOS Compatible

APPLICATIONS
USB 1.1 Signal Switching Circuits
Cell Phones
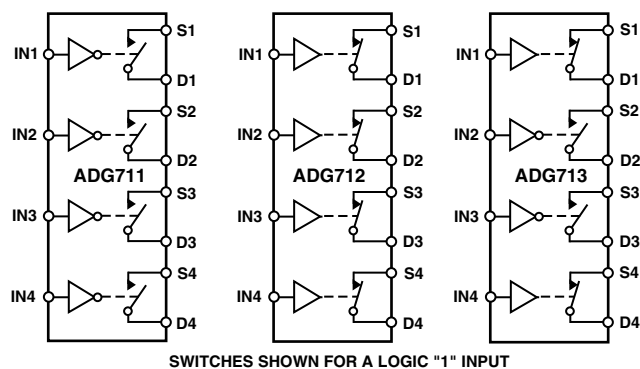PDAs
Battery-Powered Systems
Communication Systems
Sample Hold Systems
Audio Signal Routing
Video Switching
Mechanical Reed Relay Replacement

FUNCTIONAL BLOCK DIAGRAMS

SWITCHES SHOWN FOR A LOGIC "1" INPUT

GENERAL DESCRIPTION
The ADG711, ADG712, and ADG713 are monolithic CMOS devices containing four independently selectable switches. These switches are designed on an advanced submicron process that provides low power dissipation yet gives high switching speed, low on resistance, low leakage currents, and high bandwidth.

They are designed to operate from a single 1.8 V to 5.5 V supply, making them ideal for use in battery-powered instruments and with the new generation of DACs and ADCs from Analog Devices. Fast switching times and high bandwidth make the parts suitable for switching USB 1.1 data signals and video signals.

The ADG711, ADG712, and ADG713 contain four independent single-pole/single-throw (SPST) switches. The ADG711 and ADG712 differ only in that the digital control logic is inverted. The ADG711 switches are turned on with a logic low on the appropriate control input, while a logic high is required to turn on the switches of the ADG712. The ADG713 contains two switches whose digital control logic is similar to the ADG711, while the logic is inverted on the other two switches.

Each switch conducts equally well in both directions when ON. The ADG713 exhibits break-before-make switching action.

The ADG711/ADG712/ADG713 are available in 16-lead TSSOP and 16-lead SOIC packages.

PRODUCT HIGHLIGHTS
1. 1.8 V to 5.5 V Single-Supply Operation.
   The ADG711, ADG712, and ADG713 offer high performance and are fully specified and guaranteed with 3 V and 5 V supply rails.

2. Very Low R_{ON} (4.5 Ω max at 5 V, 8 Ω max at 3 V). At supply voltage of 1.8 V, R_{ON} is typically 35 Ω over the temperature range.

3. Low On Resistance Flatness.

4. –3 dB Bandwidth >200 MHz.

5. Low Power Dissipation.
   CMOS construction ensures low power dissipation.

6. Fast t_{ON}/t_{OFF}.

7. Break-Before-Make Switching.
   This prevents channel shorting when the switches are configured as a multiplexer (ADG713 only).

8. 16-Lead TSSOP and 16-Lead SOIC Packages.

REV. A

ADG711/ADG712/ADG713–SPECIFICATIONS[1]

(V_{DD} = +5 V ± 10%, GND = 0 V. All specifications –40°C to +85°C unless otherwise noted.)

Parameter	B Version +25°C	B Version –40°C to +85°C	Unit	Test Conditions/Comments
ANALOG SWITCH				
Analog Signal Range		0 V to V_{DD}	V	
On Resistance (R_{ON})	2.5		Ω typ	V_S = 0 V to V_{DD}, I_S = –10 mA;
	4	4.5	Ω max	Test Circuit 1
On Resistance Match Between		0.05	Ω typ	V_S = 0 V to V_{DD}, I_S = –10 mA
Channels (ΔR_{ON})		0.3	Ω max	
On Resistance Flatness ($R_{FLAT(ON)}$)	0.5		Ω typ	V_S = 0 V to V_{DD}, I_S = –10 mA
		1.0	Ω max	
LEAKAGE CURRENTS				V_{DD} = +5.5 V;
Source OFF Leakage I_S (OFF)	±0.01		nA typ	V_S = 4.5 V/1 V, V_D = 1 V/4.5 V;
	±0.1	±0.2	nA max	Test Circuit 2
Drain OFF Leakage I_D (OFF)	±0.01		nA typ	V_S = 4.5 V/1 V, V_D = 1 V/4.5 V;
	±0.1	±0.2	nA max	Test Circuit 2
Channel ON Leakage I_D, I_S (ON)	±0.01		nA typ	V_S = V_D = 1 V, or 4.5 V;
	±0.1	±0.2	nA max	Test Circuit 3
DIGITAL INPUTS				
Input High Voltage, V_{INH}		2.4	V min	
Input Low Voltage, V_{INL}		0.8	V max	
Input Current				
I_{INL} or I_{INH}	0.005		µA typ	V_{IN} = V_{INL} or V_{INH}
		±0.1	µA max	
DYNAMIC CHARACTERISTICS[2]				
t_{ON}	11		ns typ	R_L = 300 Ω, C_L = 35 pF,
		16	ns max	V_S = 3 V; Test Circuit 4
t_{OFF}	6		ns typ	R_L = 300 Ω, C_L = 35 pF,
		10	ns max	V_S = 3 V; Test Circuit 4
Break-Before-Make Time Delay, t_D	6		ns typ	R_L = 300 Ω, C_L = 35 pF,
(ADG713 Only)		1	ns min	V_{S1} = V_{S2} = 3 V; Test Circuit 5
Charge Injection	3		pC typ	V_S = 2 V; R_S = 0 Ω, C_L = 1 nF; Test Circuit 6
Off Isolation	–58		dB typ	R_L = 50 Ω, C_L = 5 pF, f = 10 MHz
	–78		dB typ	R_L = 50 Ω, C_L = 5 pF, f = 1 MHz; Test Circuit 7
Channel-to-Channel Crosstalk	–90		dB typ	R_L = 50 Ω, C_L = 5 pF, f = 10 MHz; Test Circuit 8
Bandwidth –3 dB	200		MHz typ	R_L = 50 Ω, C_L = 5 pF; Test Circuit 9
C_S (OFF)	10		pF typ	
C_D (OFF)	10		pF typ	
C_D, C_S (ON)	22		pF typ	
POWER REQUIREMENTS				V_{DD} = +5.5 V
I_{DD}	0.001		µA typ	Digital Inputs = 0 V or 5 V
		1.0	µA max	

NOTES
[1]Temperature range: B Version: –40°C to +85°C.
[2]Guaranteed by design, not subject to production test.

Specifications subject to change without notice.

REV. A

SPECIFICATIONS[1] $(V_{DD} = +3 V \pm 10\%, GND = 0 V.$ All specifications $-40°C$ to $+85°C$ unless otherwise noted.)

Parameter	B Version +25°C	−40°C to +85°C	Unit	Test Conditions/Comments
ANALOG SWITCH				
Analog Signal Range		0 V to V_{DD}	V	
On Resistance (R_{ON})	5	5.5	Ω typ	$V_S = 0 V$ to V_{DD}, $I_S = -10$ mA;
		8	Ω max	Test Circuit 1
On Resistance Match Between	0.1		Ω typ	$V_S = 0 V$ to V_{DD}, $I_S = -10$ mA
Channels (ΔR_{ON})		0.3	Ω max	
On Resistance Flatness ($R_{FLAT(ON)}$)		2.5	Ω typ	$V_S = 0 V$ to V_{DD}, $I_S = -10$ mA
LEAKAGE CURRENTS				$V_{DD} = +3.3 V$;
Source OFF Leakage I_S (OFF)	±0.01		nA typ	$V_S = 3 V/1 V$, $V_D = 1 V/3 V$;
	±0.1	±0.2	nA max	Test Circuit 2
Drain OFF Leakage I_D (OFF)	±0.01		nA typ	$V_S = 3 V/1 V$, $V_D = 1 V/3 V$;
	±0.1	±0.2	nA max	Test Circuit 2
Channel ON Leakage I_D, I_S (ON)	±0.01		nA typ	$V_S = V_D = 1 V$, or $3 V$;
	±0.1	±0.2	nA max	Test Circuit 3
DIGITAL INPUTS				
Input High Voltage, V_{INH}		2.0	V min	
Input Low Voltage, V_{INL}		0.4	V max	
Input Current				
I_{INL} or I_{INH}	0.005		μA typ	$V_{IN} = V_{INL}$ or V_{INH}
		±0.1	μA max	
DYNAMIC CHARACTERISTICS[2]				
t_{ON}	13		ns typ	$R_L = 300 Ω$, $C_L = 35$ pF,
		20	ns max	$V_S = 2 V$; Test Circuit 4
t_{OFF}	7		ns typ	$R_L = 300 Ω$, $C_L = 35$ pF,
		12	ns max	$V_S = 2 V$; Test Circuit 4
Break-Before-Make Time Delay, t_D	7		ns typ	$R_L = 300 Ω$, $C_L = 35$ pF,
(ADG713 Only)		1	ns min	$V_{S1} = V_{S2} = 2 V$; Test Circuit 5
Charge Injection	3		pC typ	$V_S = 1.5 V$; $R_S = 0 Ω$, $C_L = 1$ nF;
				Test Circuit 6
Off Isolation	−58		dB typ	$R_L = 50 Ω$, $C_L = 5$ pF, $f = 10$ MHz
	−78		dB typ	$R_L = 50 Ω$, $C_L = 5$ pF, $f = 1$ MHz;
				Test Circuit 7
Channel-to-Channel Crosstalk	−90		dB typ	$R_L = 50 Ω$, $C_L = 5$ pF, $f = 10$ MHz;
				Test Circuit 8
Bandwidth −3 dB	200		MHz typ	$R_L = 50 Ω$, $C_L = 5$ pF; Test Circuit 9
C_S (OFF)	10		pF typ	
C_D (OFF)	10		pF typ	
C_D, C_S (ON)	22		pF typ	
POWER REQUIREMENTS				$V_{DD} = +3.3 V$
I_{DD}	0.001		μA typ	Digital Inputs = 0 V or 3 V
		1.0	μA max	

NOTES
[1]Temperature range: B Version: −40°C to +85°C.
[2]Guaranteed by design, not subject to production test.
Specifications subject to change without notice.

ADG711/ADG712/ADG713

ABSOLUTE MAXIMUM RATINGS[1]

(T_A = +25°C unless otherwise noted)

V_{DD} to GND . . . . −0.3 V to +6 V

Analog, Digital Inputs[2] . . . . −0.3 V to V_{DD} +0.3 V or
30 mA, Whichever Occurs First

Continuous Current, S or D . . . . 30 mA

Peak Current, S or D . . . . 100 mA
(Pulsed at 1 ms, 10% Duty Cycle max)

Operating Temperature Range
Industrial (B Version) . . . . −40°C to +85°C

Storage Temperature Range . . . . −65°C to +150°C

Junction Temperature . . . . 150°C

TSSOP Package, Power Dissipation . . . . 430 mW
θ_{JA} Thermal Impedance . . . . 150°C/W
θ_{JC} Thermal Impedance . . . . 27°C/W

SOIC Package, Power Dissipation . . . . 520 mW
θ_{JA} Thermal Impedance . . . . 125°C/W
θ_{JC} Thermal Impedance . . . . 42°C/W

Lead Temperature, Soldering
Vapor Phase (60 sec) . . . . 215°C
Infrared (15 sec) . . . . 220°C

ESD . . . . 2 kV

NOTES

[1]Stresses above those listed under Absolute Maximum Ratings may cause perma-
nent damage to the device. This is a stress rating only; functional operation of the
device at these or any other conditions above those listed in the operational
sections of this specification is not implied. Exposure to absolute maximum rating
conditions for extended periods may affect device reliability. Only one absolute
maximum rating may be applied at any one time.

[2]Overvoltages at IN, S, or D will be clamped by internal diodes. Current should be
limited to the maximum ratings given.

CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily
accumulate on the human body and test equipment and can discharge without detection.
Although the ADG711/ADG712/ADG713 feature proprietary ESD protection circuitry, permanent
damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper
ESD precautions are recommended to avoid performance degradation or loss of functionality.

WARNING!
ESD SENSITIVE DEVICE

ORDERING GUIDE

Model	Temperature Range	Package Description	Package Option
ADG711BR	−40°C to +85°C	Standard Small Outline (SOIC)	R-16
ADG711BR-REEL	−40°C to +85°C	Standard Small Outline (SOIC)	R-16
ADG711BR-REEL7	−40°C to +85°C	Standard Small Outline (SOIC)	R-16
ADG711BRU	−40°C to +85°C	Thin Shrink Small Outline (TSSOP)	RU-16
ADG711BRU-REEL	−40°C to +85°C	Thin Shrink Small Outline (TSSOP)	RU-16
ADG711BRU-REEL7	−40°C to +85°C	Thin Shrink Small Outline (TSSOP)	RU-16
ADG712BR	−40°C to +85°C	Standard Small Outline (SOIC)	R-16
ADG712BR-REEL	−40°C to +85°C	Standard Small Outline (SOIC)	R-16
ADG712BR-REEL7	−40°C to +85°C	Standard Small Outline (SOIC)	R-16
ADG712BRU	−40°C to +85°C	Thin Shrink Small Outline (TSSOP)	RU-16
ADG712BRU-REEL	−40°C to +85°C	Thin Shrink Small Outline (TSSOP)	RU-16
ADG712BRU-REEL7	−40°C to +85°C	Thin Shrink Small Outline (TSSOP)	RU-16
ADG712BRUZ*	−40°C to +85°C	Thin Shrink Small Outline (TSSOP)	RU-16
ADG712BRUZ-REEL*	−40°C to +85°C	Thin Shrink Small Outline (TSSOP)	RU-16
ADG712BRUZ-REEL7*	−40°C to +85°C	Thin Shrink Small Outline (TSSOP)	RU-16
ADG713BR	−40°C to +85°C	Standard Small Outline (SOIC)	R-16
ADG713BR-REEL	−40°C to +85°C	Standard Small Outline (SOIC)	R-16
ADG713BR-REEL7	−40°C to +85°C	Standard Small Outline (SOIC)	R-16
ADG713BRU	−40°C to +85°C	Thin Shrink Small Outline (TSSOP)	RU-16
ADG713BRU-REEL	−40°C to +85°C	Thin Shrink Small Outline (TSSOP)	RU-16
ADG713BRU-REEL7	−40°C to +85°C	Thin Shrink Small Outline (TSSOP)	RU-16

*Z = Pb-free part.

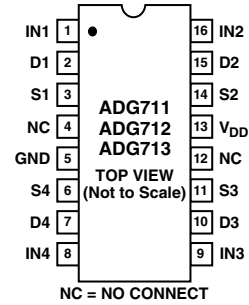**Table I. Truth Table (ADG711/ADG712)**

ADG711 In	ADG712 In	Switch Condition
0	1	ON
1	0	OFF

Table II. Truth Table (ADG713)

Logic	Switch 1, 4	Switch 2, 3
0	OFF	ON
1	ON	OFF

**PIN CONFIGURATION
(TSSOP/SOIC)**

```
        IN1 [1]  •           [16] IN2
         D1 [2]              [15] D2
         S1 [3]  ADG711      [14] S2
         NC [4]  ADG712  [13] VDD
        GND [5]  ADG713      [12] NC
         S4 [6]  TOP VIEW    [11] S3
                (Not to Scale)
         D4 [7]              [10] D3
        IN4 [8]              [9] IN3
```

NC = NO CONNECT

TERMINOLOGY

V_{DD}	Most positive power supply potential.
GND	Ground (0 V) reference.
S	Source terminal. May be an input or output.
D	Drain terminal. May be an input or output.
IN	Logic control input.
R_{ON}	Ohmic resistance between D and S.
ΔR_{ON}	On resistance match between any two channels, i.e., R_{ON}max–R_{ON}min.
$R_{FLAT(ON)}$	Flatness is defined as the difference between the maximum and minimum value of on resistance as measured over the specified analog signal range.
I_S (OFF)	Source leakage current with the switch "OFF."
I_D (OFF)	Drain leakage current with the switch "OFF."
I_D, I_S (ON)	Channel leakage current with the switch "ON."
V_D (V_S)	Analog voltage on terminals D, S.
C_S (OFF)	"OFF" switch source capacitance.
C_D (OFF)	"OFF" switch drain capacitance.
C_D, C_S (ON)	"ON" switch capacitance.
t_{ON}	Delay between applying the digital control input and the output switching on.

t_{OFF}	Delay between applying the digital control input and the output switching off.
t_D	"OFF" time or "ON" time measured between the 90% points of both switches, when switching from one address state to another. (ADG713 only).
Crosstalk	A measure of unwanted signal that is coupled through from one channel to another as a result of parasitic capacitance.
Off Isolation	A measure of unwanted signal coupling through an "OFF" switch.
Charge Injection	A measure of the glitch impulse transferred from the digital input to the analog output during switching.
Bandwidth	The frequency at which the output is attenuated by 3 dB.
On Response	The frequency response of the "ON" switch.
On Loss	The voltage drop across the "ON" switch, seen on the on response vs. frequency plot as how many dBs the signal is away from 0 dB at very low frequencies.

Figure 1. On Resistance as a Function of V_D (V_S)

Figure 2. On Resistance as a Function of V_D (V_S) for Different Temperatures V_{DD} = 3 V

Figure 3. On Resistance as a Function of V_D (V_S) for Different Temperatures V_{DD} = 5 V

Figure 4. Supply Current vs. Input Switching Frequency

Figure 5. Off Isolation vs. Frequency
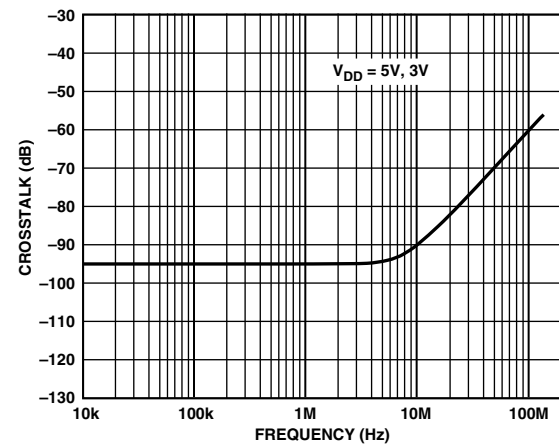
Figure 6. Crosstalk vs. Frequency
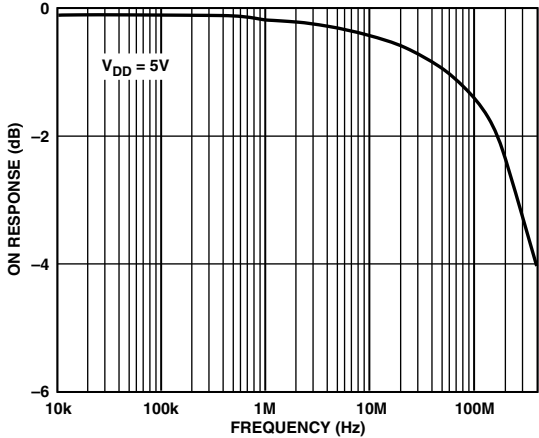
Figure 7. On Response vs. Frequency
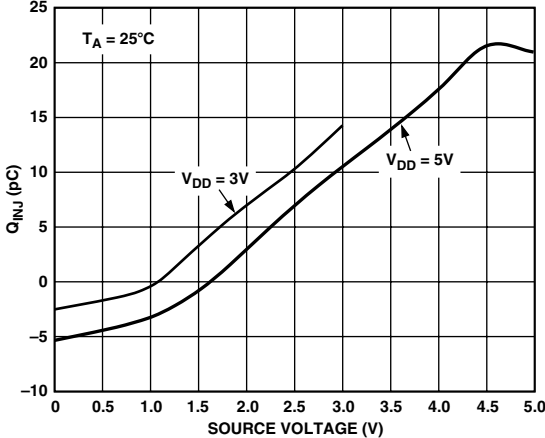
Figure 8. Charge Injection vs. Source Voltage

APPLICATIONS

Figure 9 illustrates a photodetector circuit with programmable gain. An AD820 is used as the output operational amplifier. With the resistor values shown in the circuit, and using different combinations of the switches, gain in the range of 2 to 16 can be achieved.
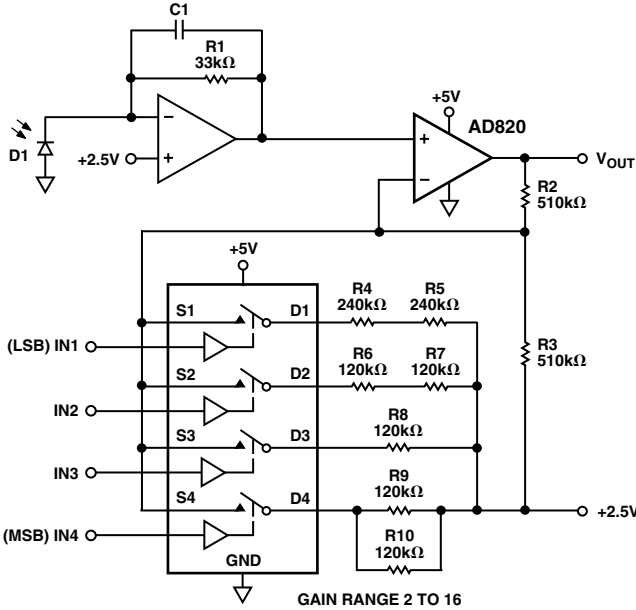
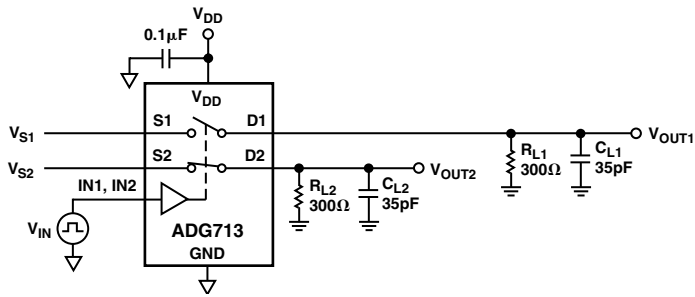Figure 9. Photodetector Circuit with Programmable Gain
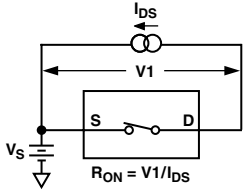
Test Circuits

Test Circuit 1. On Resistance
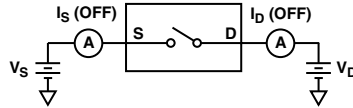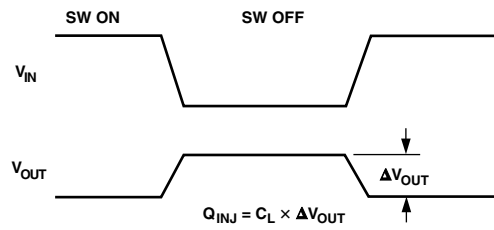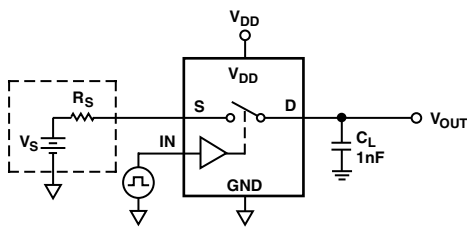

Test Circuit 2. Off Leakage
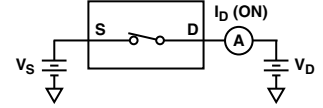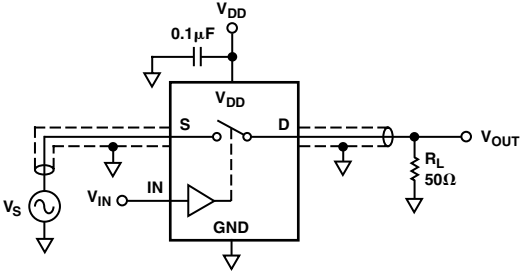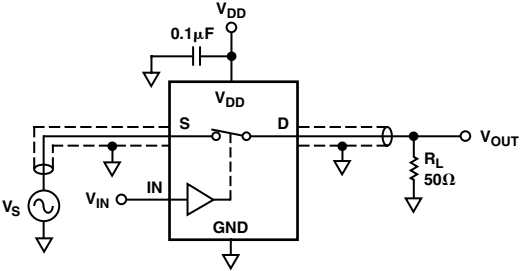

Test Circuit 3. On Leakage
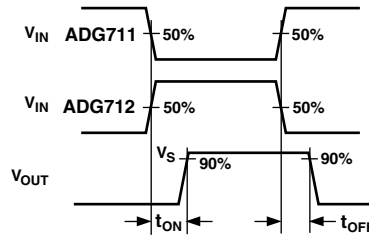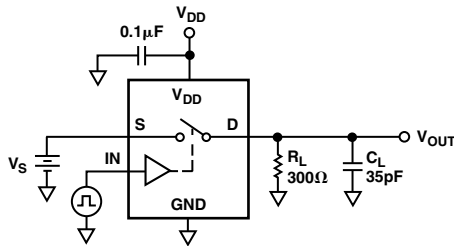
Test Circuit 4. Switching Times
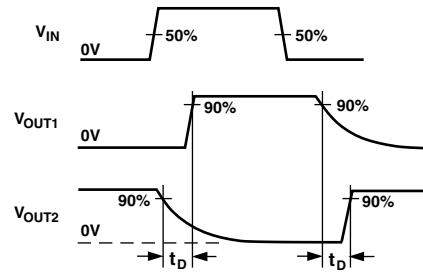
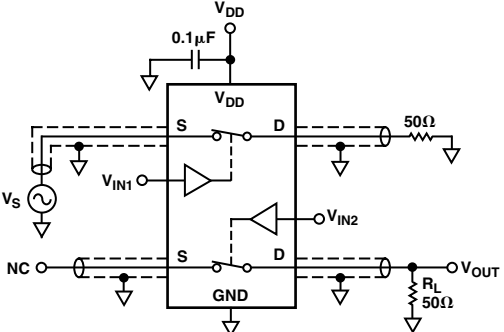*Test Circuit 5. Break-Before-Make Time Delay, t_D*

Test Circuit 6. Charge Injection

Test Circuit 7. Off Isolation
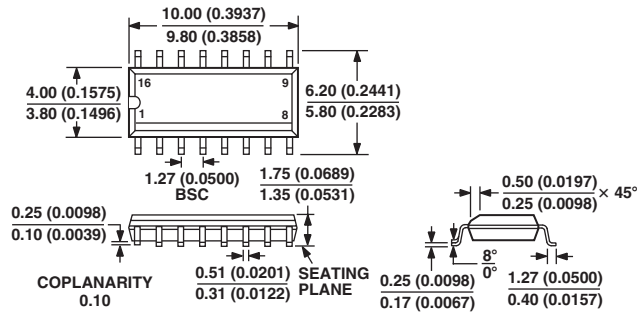

Test Circuit 9. Bandwidth

CHANNEL-TO-CHANNEL CROSSTALK = $20 \times LOG\ |V_S/V_{OUT}|$

Test Circuit 8. Channel-to-Channel Crosstalk

ADG711/ADG712/ADG713

16-Lead Standard Small Outline Package [SOIC]
Narrow Body
(R-16)

Dimensions shown in millimeters and (inches)

10.00 (0.3937)
9.80 (0.3858)

4.00 (0.1575)
3.80 (0.1496)

16
9

1
8

6.20 (0.2441)
5.80 (0.2283)

1.27 (0.0500)
BSC

1.75 (0.0689)
1.35 (0.0531)

0.50 (0.0197)
0.25 (0.0098) × 45°

0.25 (0.0098)
0.10 (0.0039)

COPLANARITY
0.10

0.51 (0.0201)
0.31 (0.0122)

SEATING
PLANE

0.25 (0.0098)
0.17 (0.0067)

8°
0°

1.27 (0.0500)
0.40 (0.0157)

COMPLIANT TO JEDEC STANDARDS MS-012AC
CONTROLLING DIMENSIONS ARE IN MILLIMETERS; INCH DIMENSIONS
(IN PARENTHESES) ARE ROUNDED-OFF MILLIMETER EQUIVALENTS FOR
REFERENCE ONLY AND ARE NOT APPROPRIATE FOR USE IN DESIGN

16-Lead Thin Shrink Small Outline Package [TSSOP]
(RU-16)

Dimensions shown in millimeters

5.10
5.00
4.90

16
9

1
8

4.50
4.40
4.30

6.40
BSC

PIN 1

1.20
MAX

0.15
0.05

0.65
BSC

0.30
0.19

COPLANARITY
0.10

SEATING
PLANE

0.20
0.09

8°
0°

0.75
0.60
0.45
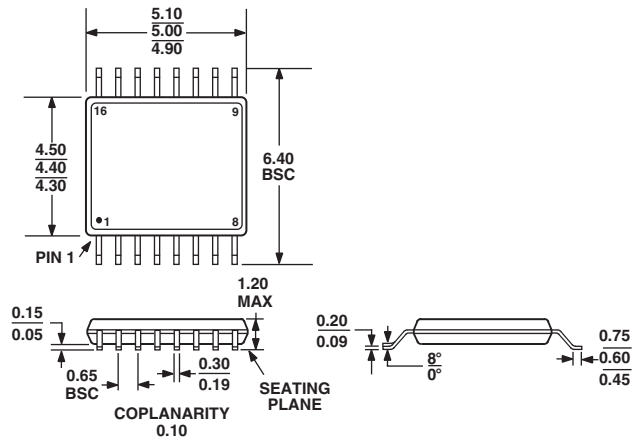
COMPLIANT TO JEDEC STANDARDS MO-153AB

REV. A

Revision History